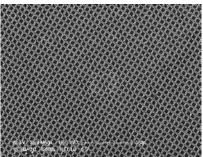


TECHNICAL NOTES

500NM SEM MAGNIFICATION CALIBRATION DIFFRACTION GRATING REPLICA PRODUCT NO. 674, 674-A TO R

This specimen is a replica of a 2,000 lines/mm cross line diffraction grating. Replica is mounted on a 400 mesh copper TEM grid with a diameter of 3mm. When imaging the specimen, the line spacing is 500nm +/-1%; and the pattern will be visible at approximately 2,000x. At this magnification the lines of the pattern will be 1mm apart.



- To calculate the electron microscope magnification using the pattern of the diffraction grating replica:
- Take the measurement, in millimeters of as many squares and lines of the replica pattern as possible. The line is a trench type groove. Always measure the same sides of the lines. Apply the following formula:
 - Magnification = $A \times 2000/B$
- A is distance in mm between limiting lines.
- B is number of spaces between limiting lines.
- (Alternatively, use the PELCO® Magnification Calibration Calculator, Prod. No. 253)

Care of Grating Replica Specimen

When not in use the replica should be kept in a dry and dust-free container. The replica surface may be damaged if touched. Never try to clean it. Dust can be removed using a rubber bulb attached to a glass pipette. Use a gentle stream of air.

674-A-R TN V2 0414

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